

December 2009

# FDME1023PZT

# Dual P-Channel PowerTrench<sup>®</sup> MOSFET -20 V, -2.3 A, 142 m $\Omega$

### **Features**

- Max  $r_{DS(on)}$  = 142 m $\Omega$  at  $V_{GS}$  = -4.5 V,  $I_D$  = -2.3 A
- Max  $r_{DS(on)}$  = 213 m $\Omega$  at  $V_{GS}$  = -2.5 V,  $I_D$  = -1.8 A
- Max  $r_{DS(on)} = 331 \text{ m}\Omega$  at  $V_{GS} = -1.8 \text{ V}$ ,  $I_D = -1.5 \text{ A}$
- Max  $r_{DS(on)}$  = 530 m $\Omega$  at  $V_{GS}$  = -1.5 V,  $I_D$  = -1.2 A
- Low profile: 0.55 mm maximum in the new package MicroFET 1.6x1.6 **Thin**
- Free from halogenated compounds and antimony oxides
- HBM ESD protection level > 1600V (Note3)
- RoHS Compliant



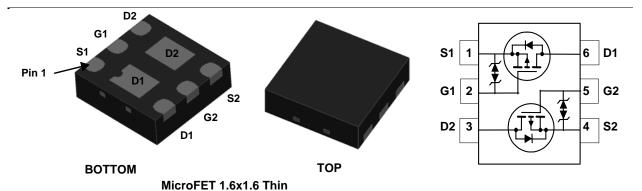
### **General Description**

This device is designed specifically as a single package solution for the battery charges switch in cellular handset and other ultra-portable applications. It features two independent P-Channel MOSFETs with low on-state resistance for minimum conduction losses. When connected in the typical common source configuration, bi-directional current flow is possible.

The MicroFET 1.6x1.6 **Thin** package offers exceptional thermal performance for it's physical size and is well suited to switching and linear mode applications.

### **Applications**

- Load Switch
- Battery Charging
- Battery Disconnect Switch



## MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage			-20	V	
V <sub>GS</sub>	Gate to Source Voltage			±8	V	
1	Drain Current -Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	-2.3	^	
ID	-Pulsed			-6	Α	
D	Power Dissipation for Single Operation	T <sub>A</sub> = 25 °C	(Note 1a)	1.3	10/	
$P_{D}$	Power Dissipation for Single Operation	T <sub>A</sub> = 25 °C	(Note 1b)	0.6	W	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C	

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1a)	95	°C/W
Rela	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1b)	210	C/VV

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
2T	FDME1023PZT	MicroFET 1.6x1.6 <b>Thin</b>	7 "	8 mm	5000 units

# **Electrical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = -250 \mu\text{A},  V_{GS} = 0 \text{V}$	-20			V
$\Delta BV_{DSS} \ \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25 °C		-12		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -16 V, V <sub>GS</sub> = 0 V			-1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

### **On Characteristics**

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.4	-0.6	-1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = -250 μA, referenced to 25 °C		2		mV/°C
	$V_{GS} = -4.5 \text{ V}, I_D = -2.3 \text{ A}$		95	142		
		$V_{GS} = -2.5 \text{ V}, I_D = -1.8 \text{ A}$		120	213	
rno( )	Drain to Source On Resistance	$V_{GS} = -1.8 \text{ V}, I_D = -1.5 \text{ A}$		150	331	mΩ
r <sub>DS(on)</sub>	Brain to Godice on Nesistano	$V_{GS} = -1.5 \text{ V}, I_D = -1.2 \text{ A}$		190	530	11132
		$V_{GS} = -4.5 \text{ V}, I_D = -2.3 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$		128	190	
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -4.5 \text{ V}, I_{D} = -2.3 \text{ A}$		7		S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 40.V V 0.V	305	405	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	55	75	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 101112	50	75	pF

### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		4.7	10	ns
t <sub>r</sub>	Rise Time	$V_{DD} = -10 \text{ V}, I_{D} = -1 \text{ A}$ $V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$	4.8	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6.22$	33	53	ns
t <sub>f</sub>	Fall Time		16	29	ns
$Q_g$	Total Gate Charge	V 40 V 1 00 A	5.5	7.7	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DD} = -10 \text{ V}, I_{D} = -2.3 \text{ A}$ $V_{GS} = -4.5 \text{ V}$	0.6		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	VGS = -4.5 V	1.4		nC

### **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -0.9 \text{ A}$ (Note 2)		-0.8	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	$I_E = -2.3 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s}$		16	29	ns
Q <sub>rr</sub>	Reverse Recovery Charge	1 <sub>F</sub> = -2.5 A, α//αι = 100 A/μs		4.4	10	nC

<sup>1.</sup> R<sub>0JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a.95 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 210 °C/W when mounted on a minimum pad of 2 oz copper.

<sup>2.</sup> Pulse Test: Pulse Width <  $300\mu s,$  Duty cycle < 2.0%.

<sup>3.</sup> The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

# Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

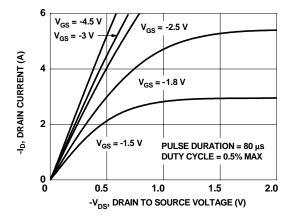


Figure 1. On Region Characteristics

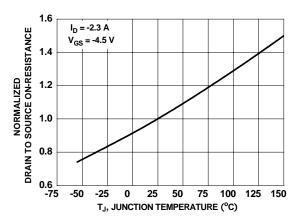


Figure 3. Normalized On Resistance vs Junction Temperature

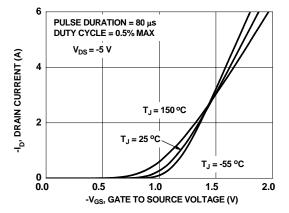


Figure 5. Transfer Characteristics

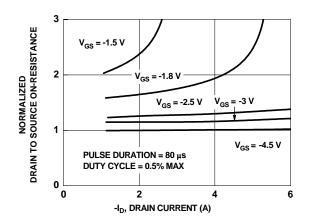


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

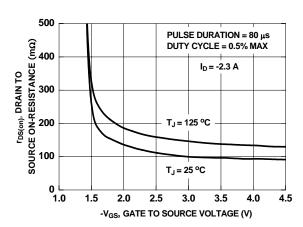


Figure 4. On-Resistance vs Gate to Source Voltage

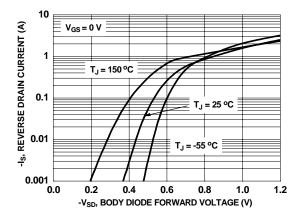


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

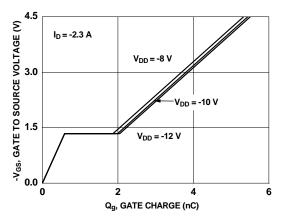


Figure 7. Gate Charge Characteristics

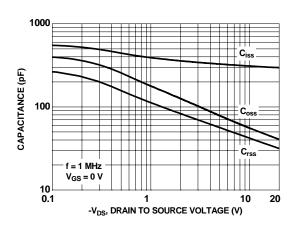


Figure 8. Capacitance vs Drain to Source Voltage

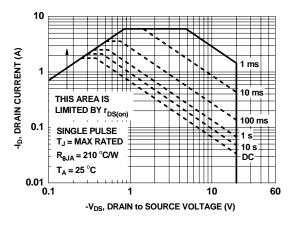


Figure 9. Forward Bias Safe Operating Area

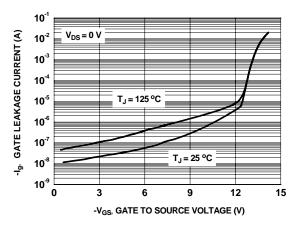


Figure 10. Gate Leakage Current vs Gate to Source Voltage

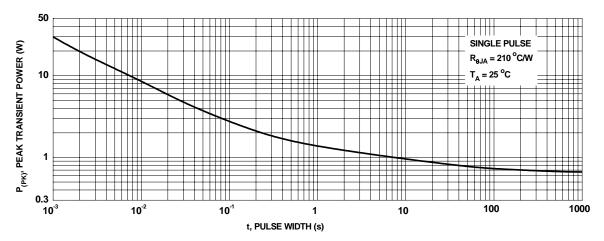


Figure 11. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

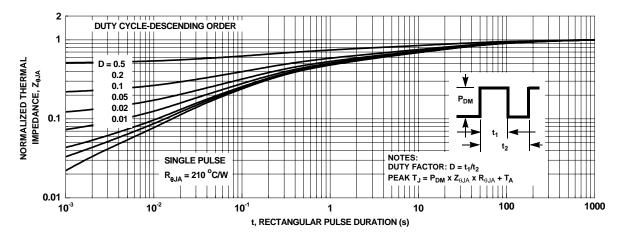
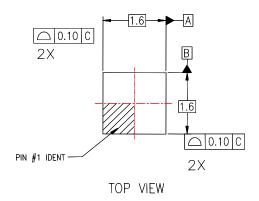
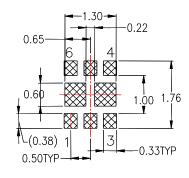


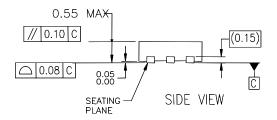
Figure 12. Junction-to-Ambient Transient Thermal Response Curve

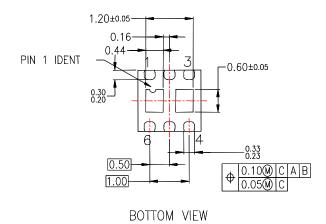
# **Dimensional Outline and Pad Layout**





RECOMMENDED LAND PATTERN









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